

**Notice of References Cited**

Application/Control No.

10/649,613

Applicant(s)/Patent Under  
Reexamination  
FUJISAKI ET AL.

Examiner

N. Drew Richards

Art Unit

2815

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,368,923 B1	04-2002	Huang, Kuo-Tai	438/275
	B	US-6,610,614	08-2003	Niimi et al.	438/775
	C	US-6,136,654 A	10-2000	Kraft et al.	438/287
	D	US-6,337,289	01-2002	Narwankar et al.	438/776
	E	US-6,348,420 B1	02-2002	Raaijmakers et al.	438/769
	F	US-2002/0111000	08-2002	Kawakami et al.	438/584
	G	US-2002/0119673	08-2002	Yieh et al.	438/758
	H	US-6,399,445 B1	06-2002	Hattangady et al.	438/261
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000269483 A	09-2000	Japan	NAKANISHI et al.	H01L 29/78
	O	JP 58040833 A	03-1983	Japan	TAKEUCHI et al.	H01L 21/318
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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